

	Type	L #	Hits	Search Text	DBs	Time Stamp
1	BRS	L2	0	1 and multiple near light near optics	USPAT; US-PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2002/09/30 18:50
2	BRS	L1	124	inspecting near3 wafer and detecting near defects	USPAT; US-PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2002/09/30 18:50

	Comments	Error Definition	Errors
1			0
2			0